Docket No. 1422-0603P Appl. No. 10/668,216

## AMENDMENTS TO THE CLAIMS

1. (Currently Amended) A polishing composition comprising polymer particles and inorganic particles in an aqueous medium, wherein the inorganic particles have an average particle size of from 5 to 170 95 nm, and wherein an average particle size Dp (nm) of said polymer particles and an average particle size Di (nm) of said inorganic particles satisfy the following formula (1):

$$Dp \le Di + 50 \text{ nm} \tag{1}$$

wherein the polymer particles and the inorganic particles are colloidal silica have a zeta potential of zero or the same sign.

- (Original) The polishing composition according to claim
  wherein the polymer particles are made of a thermoplastic resin.
- 3. (Original) The polishing composition according to claim 1, wherein the polymer particles are made of a resin having a glass transition temperature of 200°C or less.
- 4. (Original) The polishing composition according to claim 1, wherein the polymer particles are made of a resin having a degree of cross-linking of 50 or less.

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- 5. (Currently Amended) The polishing composition according to claim 1, wherein the polymer particles and the inorganic particles are colloidal silica have a zeta potential of zero or the same sign.
- 6. (Original) The polishing composition according to claim 1, wherein a ratio of Cp/Ci is from 0.03 to 2, wherein Cp is a content of the polymer particles in the polishing composition and Ci is a content of the inorganic particles in the polishing composition.
- 7. (Original) A polishing process for a substrate to be polished comprising polishing the substrate to be polished with the polishing composition as defined in any one of claims 1 to 6.
- 8. (Currently Amended) A process for improving a rate for polishing a substrate to be polished with using the polishing composition as defined in any one of claims 1 to 6.
- 9. (Previously Presented) The polishing process according to claim 7, wherein the substrate to be polished is a substrate having silicon dioxide.

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10. (Previously Presented) The polishing process according to claim 7, wherein the substrate to be polished is an aluminum alloy substrate plated with Ni-P.

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